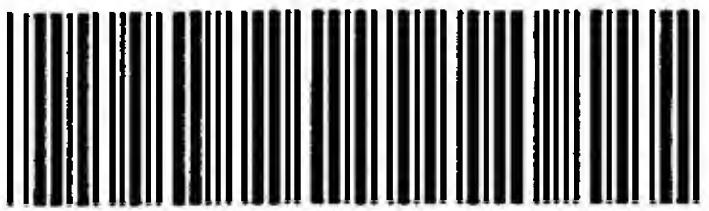


Search Notes

Application/Control No.

10/708,834

Examiner

Nam V. Nguyen

Applicant(s)/Patent under
Reexamination

BEENAU ET AL.

Art Unit

2635

SEARCHED

Class	Subclass	Date	Examiner
340	5.53	1/17/2006	NN
340	5.2	1/17/2006	NN
340	5.4+	1/17/2006	NN
340	5.52	1/17/2006	NN
340	5.6	1/17/2006	NN
340	5.6+	1/17/2006	NN
340	10.1	1/17/2006	NN
340	10.4-10.6	1/17/2006	NN
235	379	1/17/2006	NN
235	380	1/17/2006	NN
235	492	1/17/2006	NN
705	35,54,76	1/17/2006	NN
705	185	1/17/2006	NN
705	194	1/17/2006	NN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search: USPAT; US-PUB; EPO; JPO; and Derwent	1/17/2006	NN